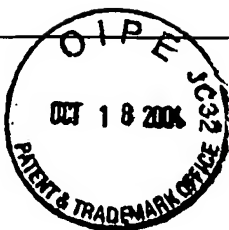


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**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: Kraft, Raymond H.
Appln. No.: 10/800,420
Filing Date: March 12, 2004
Examiner: Group Art Unit: 2621

Date: October 13, 2004 Page 1 of 1

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Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
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	PR				

Examiner /John Lee/ Date Considered: 10/11/2007

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.